

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/633,718	TERAUE, EIJI	
Examiner		Art Unit		Page 1 of 1
Beniyam Menberu		2625		

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,936,749	08-1999	Ikeda, Iwata	358/515
*	B	US-6,226,103	05-2001	Klassen et al.	358/1.9
*	C	US-7,032,517	04-2006	Bestmann, Gu	101/484
*	D	US-7,158,670	01-2007	Fushiki et al.	382/167
*	E	US-2002/0159083 A1	10-2002	Arai et al.	358/1.9
*	F	US-7,068,391	06-2006	Dewitte et al.	358/1.9
*	G	US-6,304,345	10-2001	Patton et al.	358/527
*	H	US-2004/0001208 A1	01-2004	Murakami, Hirokazu	358/1.9
*	I	US-2003/0016942 A1	01-2003	Tojo et al.	386/46
*	J	US-2003/0197878 A1	10-2003	Metois et al.	358/1.9
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 04-284579	10-1992	Japan	Yamada, Osamu	G06F 15/66
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.